Journal of VOLUME 32 · NO 5 MARCH 14, 2017 MATERIALS RESEARCH

FOCUS ISSUE Aberration Corrected Transmission Electron Microscopy

MRS MATERIALS RESEARCH SOCIETY Advancing materials, Improving the quality of life



Journal of MATERIALS RESEARCH

JOURNAL OF MATERIALS RESEARCH (*JMR*) is an interdisciplinary journal serving the materials research community through publication of original research articles and invited reviews encompassing the synthesis, processing, characterization, properties, and theoretical description of materials.

JMR publishes new research that demonstrates a significant impact or advance of scientific understanding of interest to the materials research community. Engineering studies and applications to commercial products are beyond the scope of *JMR* and should be submitted elsewhere. Manuscripts that report data without giving an analysis, interpretation, or discussion are only acceptable if the data are sufficiently important that publication is expected to lead to significant new studies or advancements in science or technology.

Manuscripts must be submitted to the *Journal of Materials Research* electronically via ScholarOne manuscripts, at the following website address: http://mc.manuscriptcentral.com/jmr. Electronic submission expedites the review process and also allows authors to track the status of their manuscripts at any time. Complete instructions are available on the ScholarOne site and authors will be prompted to provide all necessary information.

Manuscripts must be prepared in English, using a word processing program, formatted to fit $8\frac{1}{2} \times 11$ in. paper, and saved as .doc, .pdf, .rtf, or .ps files. Separate graphics files (.eps and .tif) must be uploaded for each figure. Authors may also upload .xls or .ppt supplemental files as part of the manuscript submission process. All of these files will be converted to .pdf format. Detailed instructions are available on the submission web site. During submission, authors must enter all coauthor names and e-mail addresses. Manuscripts will not be considered for peer review until this information is provided. Authors must also enter manuscript keywords using the *JMR* keyword list (located on the submission we b site). Authors who are not fluent in English must have their manuscript edited for correct English grammar and sentence structure before submission.

Authors are expected to follow the conventional writing, notation, and illustration style prescribed in *Scientific Style and Format: the CSE Manual for Authors, Editors and Publishers, 7th edition, 2006.* Authors should also study the form and style of printed material in this journal. SI units should be used. Authors should use an identical format for their names in all publications to facilitate use of citations and author indexes.

Manuscripts are accepted with the understanding that they represent original research, except for review articles, and that they have not been copyrighted, published, or submitted for publication elsewhere. Authors submitting manuscripts to *JMR* who have related material under consideration or in press elsewhere should send a copy of the related material to *JMR* at the time of submission. While their manuscripts are under consideration at *JMR*, authors must disclose any such related material. To expedite the review process, authors may provide names and contact information for up to four possible reviewers.

Articles are original research reports that include complete, detailed, self-contained descriptions of research efforts. All articles must contain an abstract and section headings.

Commentaries and Reviews: *Journal of Materials Research* occasionally publishes commentaries on topics of current interest or reviews of the literature in a given area. If an author proposes a review, the title, abstract, and a brief outline should be submitted to the Editorial Office via e-mail for prior consultation on the appropriateness of the topic.

Color policy: It is not necessary for authors to indicate that a figure should be displayed in color online. *JMR* will assume that any author who submits figures in color wants and agrees to their being produced in color online. Figures may be printed in color at the author's request for an additional charge. Color figures must be submitted before the paper is accepted for publication, and cannot be received later in the process. Authors cannot submit two versions of the same figure, one for color and one for black and white; only one version can be submitted. Authors need to carefully consider the following when submitting figures in color that will

be published in color online only: 1) The colors chosen must reproduce effectively and the colors should be distinguishable when printed in black and white; 2) The descriptions of figures in text and captions must be sufficiently clear for both online and print copy. When submitting figures to be in color online only, authors should include the phrase <<color online>> in the figure captions. This is the author's responsibility. Authors will see these color figures when viewing their author page proofs on screen. Authors should always print their page proofs in black and white to see how they will appear in print. Authors will NOT be allowed to submit color figures to replace black and white figures in the page proof stage. To maximize the probability that figures will be published in color online and also print as good quality black and white or grayscale graphics, authors are encouraged to follow these figure submission guidelines: 1) Submit a color graphic in Tagged Image File Format (.tif); 2) Submit color graphics with a resolution of at least 300 dpi (600 dpi if there is text or line art in the figure); 3) Submit color graphics in CMYK format; 4) Submit figures sized to fit the actual column or page width of the journal so that reduction or enlargement is not necessary; 5) Submit multipart figures in one single electronic file.

Copyright © 2017, Materials Research Society. All rights reserved. No part of this publication may be reproduced, in any form or by any means, electronic, photocopying, or otherwise, without permission in writing from Cambridge University Press. Policies, request forms and contacts are available at: http://www.cambridge.org/rights/permissions/permission. htm. Permission to copy (for users in the USA) is available from Copyright Clearance Center at: http://www.copyright.com, email: info@ copyright.com.

Journal of Materials Research Subscription Prices (2017) [includes on-line web access] USA and Poss. Online Online WRS Regular and Student Members \$273.00 \$334.00 \$105.00

Institutions \$2053.00 \$2053.00 \$1852.00 Journal of Materials Research (ISSN: 0884-2914) is published twenty-four times a year by Cambridge University Press, One Liberty Plaza, 20th Floor, New York, NY 10006 for the Materials Research Society. Periodical Postage Paid in New York, NY and additional mailing offices. **POSTMASTER:** Send address changes to Journal of Materials Research, c/o Journals Dept., Cambridge University Press, One Liberty Plaza, 20th

Floor, New York, NY 10006, USA.

Subscriptions, renewals, address changes, and single-copy orders should be addressed to Subscription Fulfillment, *Journal of Materials Research*, Cambridge University Press, One Liberty Plaza, 20th Floor, New York, NY 10006, USA (for USA, Canada, and Mexico); or Cambridge University Press, University Printing House, Shaftesbury Road, Cambridge, CB2 8BS, England (for UK and elsewhere). Allow at least six weeks advance notice. For address changes, please send both old and new addresses and, if possible, include a mailing label from a recent issue. Requests from subscribers for missing journal issues will be honored without charge only if received within six months of the issue's actual date of publication; otherwise, the issue may be purchased at the single-copy price.

Reprints of individual articles in *Journal of Materials Research* may be ordered. For information on reprints, please contact Cambridge University Press. Reprints of complete back issues older than the prior volume year may be ordered on an individual basis via the Cambridge Journals Online website. To determine availability, visit the appropriate page for the *JMR* back issue desired (cambridge.org/journal-of-materials-research).

Individual member subscriptions are for personal use only.

Journal of MATERIALS RESEARCH

Editor-in-Chief: Gary L. Messing, Ceramic materials, The Pennsylvania State University, USA Associate Editor, Adrian Mann, Biomaterials, Rutgers University, USA Associate Editor, Jürgen Eckert, Metallic materials, Montanuniversität Leoben, Austria Associate Editor, Linda S. Schadler, Polymeric materials, Rensselaer Polytechnic Institute, USA

Guest Editors for Focus Issue: Aberration Corrected Transmission Electron Microscopy

Thomas Walther, University of Sheffield, United Kingdom Rafal E. Dunin-Borkowski, Research Centre Jülich, Germany Jean-Luc Rouvière, CEA Grenoble, France Eric A. Stach, Brookhaven National Laboratory, USA

2017 Principal Editors:

Jinju Chen, Mechanics of soft materials/thin film materials, Nanoindentation Newcastle University, United Kingdom Xiaobo Chen, Photocatalysis and batteries, University of Missouri-Kansas City, USA Yang-T. Cheng, Mechanical behavior, Electrochemical energy storage, University of Kentucky, USA Sung-Yoon Chung, Energy, Electron microscopy, Interface science, KAIST, Korea Paolo Colombo, Preceramic polymers, Porous ceramics, University of Padova, Italy; The Pennsylvania State University, USA Franz Faupel, Functional nanomaterials, VPD, Metallic glasses, University of Kiel, Germany Mathias Göken, Superalloys, Nanomaterials, Nanomechanics, Friedrich-Alexander-Universität Erlangen-Nürnberg, Germany Amit Goyal, Superconductors, Photovoltaics, 2D materials, Self-assembly, State University of New York at Buffalo, USA Erik G. Herbert, Nanoindentation, Small-scale mechanical behavior Michigan Technological University, USA Himanshu Jain, Inorganic glass, Optical, Electrical properties, Lehigh University, USA C. Robert Kao, Metallic materials, Diffusion and joining, National Taiwan University. Taiwan Edson Roberto Leite, Materials chemistry, Nanocrystals, Synthesis, Universidade Federal de São Carlos, Brazil Jörg Löffler, Metallic materials/synthesis and properties, ETH Zurich, Switzerland Michele Manuel, Phase transformations, Materials design, University of Florida, USA Michael E. McHenry, Magnetic materials, Carnegie Mellon University, USA Scott T. Misture, In-situ diffraction, Electrochemically active ceramics, Alfred University, USA Sarah E. Morgan, Polymer surfaces and interfaces,

The University of Southern Mississippi, USA

Ecole Polytechnique Federale de Lausanne, Switzerland Akira Nakajima, Photocatalysis, Surface wettability, Ceramic processing, Tokyo Institute of Technology, Japan Cewen Nan, Ferroelectric, Multiferroic materials, Tsinghua University, China George M. Pharr, Mechanical behavior, Nanoindentation, University of Tennessee, USA

Paul Muralt, Thin films, Piezoelectric and ferroelectric materials,

- Ian M. Reaney, *Electroceramics, TEM, Thin films,* The University of Sheffield, United Kingdom
- Edward M. Sabolsky, *Electroceramics, Electrochemistry, Processing,* West Virginia University, USA

Winston Schoenfeld, Optical materials, University of Central Florida, USA

Don W. Shaw, Epitaxy, Vapor deposition, Semiconductors, The University of Texas at Dallas, USA

Susan B. Sinnott, *Computational materials science, The Pennsylvania State University, USA*

- Mauricio Terrones, Nanocarbon, Graphene, 2-D metal chalcogenides, The Pennsylvania State University, USA; Shinshu University, Japan
- Terry M. Tritt, Thermoelectrics, Clemson University, USA
- Chongmin Wang, Energy storage, Microscopy, In-situ/operando technique, Pacific Northwest National Laboratory, USA
- William J. Weber, Radiation effects, Nuclear ceramics, University of Tennessee; Oak Ridge National Laboratory, USA
- Tao Xie, Polymers, Functional soft materials, Zhejiang University, China

Sam Zhang, Thin films/coatings, Nanyang Technological University, Singapore

Yanchun Zhou, Structural ceramics, Electronic structure, Aerospace Research Institute of Materials and Processing Technology, China

Editorial Office: Ellen W. Kracht, Publications Manager, Materials Research Society, Warrendale, PA Linda A. Baker, JMR Editorial Assistant, Materials Research Society, Warrendale, PA Kirby L. Morris, JMR Production Assistant, Materials Research Society, Warrendale, PA Eileen M. Kiley, Director of Communications, Materials Research Society, Warrendale, PA

Journal of MATERIALS RESEARCH

Volume 32, Number 5, March 14, 2017

ABERRATION CORRECTED TRANSMISSION ELECTRON MICROSCOPY

911	Introduction	Thomas Walther, Rafal E. Dunin-Borkowski, Jean-Luc Rouvière, Eric A. Stach
INVITED ARTICLE		
912–920	Recent studies of oxide-semiconductor heterostructures using aberration-corrected scanning transmission electron microscopy	David J. Smith, HsinWei Wu, Sirong Lu, Toshihiro Aoki, Patrick Ponath, Kurt Fredrickson, Martin D. McDaniel, Edward Lin, Agham B. Posadas, Alexander A. Demkov, John Ekerdt, Martha R. McCartney
INVITED FEATURE PAPER		
921–927	Observation of compound semiconductors and heterovalent interfaces using aberration-corrected scanning transmission electron microscopy	David J. Smith, Jing Lu, Toshihiro Aoki, Martha R. McCartney, Yong-Hang Zhang
REVIEW		
928–935	New insights on ion track morphology in pyrochlores by aberration corrected scanning transmission electron microscopy	Ritesh Sachan, Yanwen Zhang, Xin Ou, Christina Trautmann, Matthew F. Chisholm, William J. Weber
ARTICLES		
936–946	Comparison of convergent beam electron diffraction and annular bright field atomic imaging for GaN polarity determination	Alexana Roshko, Matt D. Brubaker, Paul T. Blanchard, Kris A. Bertness, Todd E. Harvey, Roy H. Geiss, Igor Levin
947–956	An effect of crystal tilt on the determination of ions displacements in perovskite oxides under BF/HAADF-STEM imaging mode	Y. Liu, Y.L. Zhu, Y.L. Tang, X.L. Ma
957–967	3D polarization texture of a symmetric 4-fold flux closure domain in strained ferroelectric PbTiO ₃ films	Y.L. Tang, Y.L. Zhu, Z.J. Hong, E.A. Eliseev, A.N. Morozovska, Y.J. Wang, Y. Liu, Y.B. Xu, B. Wu, L.Q. Chen, S.J. Pennycook, X.L. Ma
968–982	Beam-induced atomic migration at Ag-containing nanofacets at an asymmetric Cu grain boundary	Nicolas J. Peter, Christian H. Liebscher, Christoph Kirchlechner, Gerhard Dehm
983–995	Study of phase separation in an InGaN alloy by electron energy loss spectroscopy in an aberration corrected monochromated scanning transmission electron microscope	Thomas Walther, Xiaoyi Wang, Veerendra C. Angadi, Pierre Ruterana, Paolo Longo, Toshihiro Aoki
996–1008	Aberration-corrected self-interference of split higher order Laue zone line for measuring the <i>z</i> -dependent strain profile	Mana Norouzpour, Rodney Herring